

Research Fab Germany (FMD): Bridging Chip Design to Applications Through Heterogeneous Integration

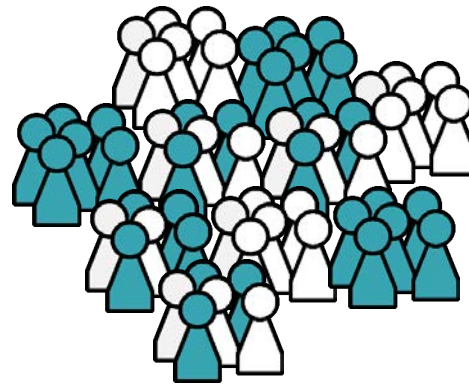
Prof. Dr. Albert Heuberger

- Spokesman of the Fraunhofer Group for Microelectronics and Chairman of the steering committee of the Research Fab Microelectronics Germany
- Executive Director of the Fraunhofer Institute for Integrated Circuits IIS
- Head of the Chair of Information Technologies at the Friedrich-Alexander-Universität Erlangen-Nürnberg





FMD combines the expertise and infrastructure of **13 research institutes** across Germany and offers developments **along the entire value chain in a one-stop shop.**



FMD at a glance:

3,000 m EUR in assets
3,500 employees FTE,
2,000+ scientists
600 m EUR/yr
250 m EUR/yr from Industry
From TRL2 to TRL8

Total investment of EUR 350 million for additional infrastructure and future developments.
(1.4.2017-30.9.2021)

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Federal Ministry
of Education
and Research

International establishment of FMD and **cooperation with European partners** (e.g. NGC Alliance).





Extended CMOS



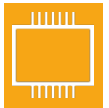
Optoelectronic Systems



Power Electronics



MEMS Actuators

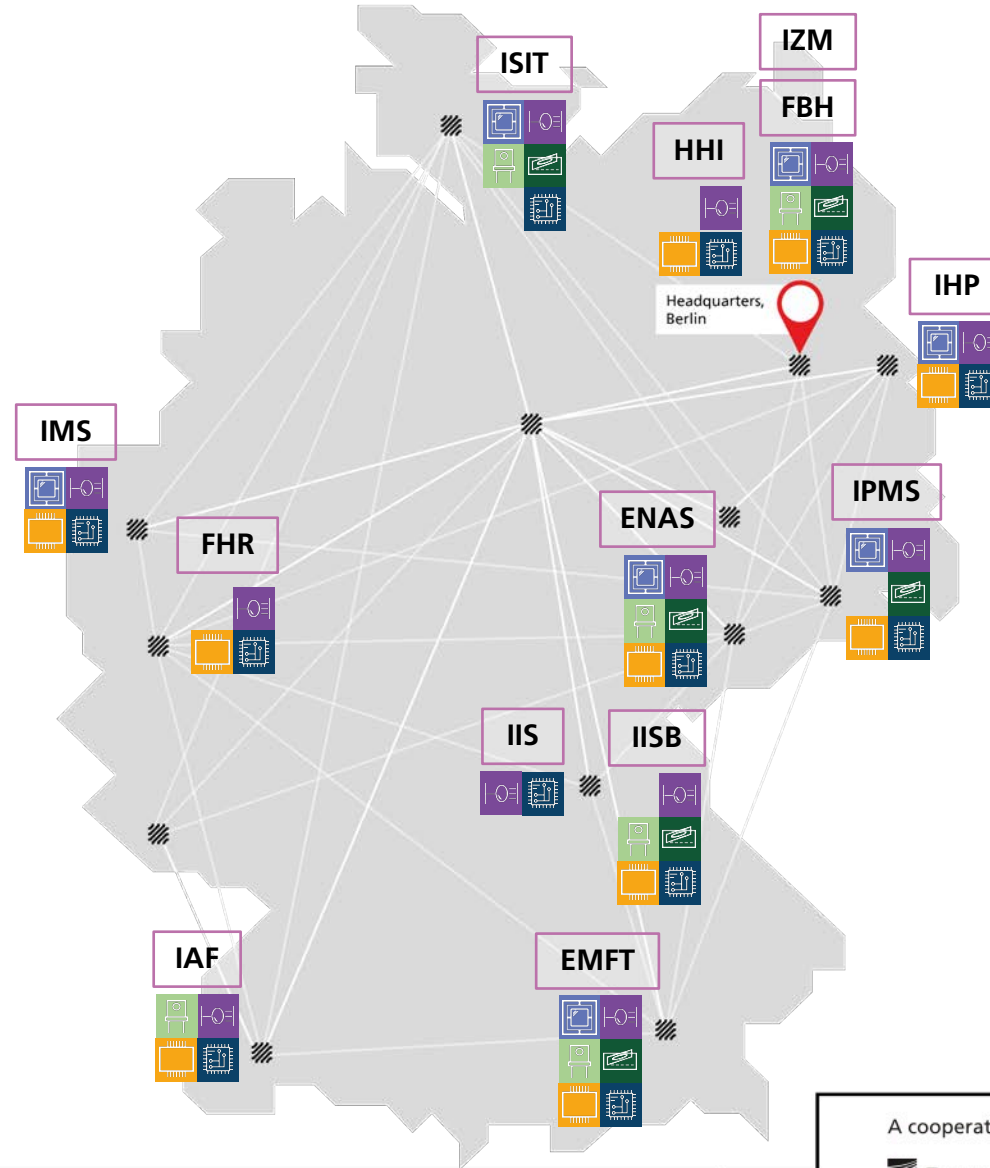


Microwave and Terahertz



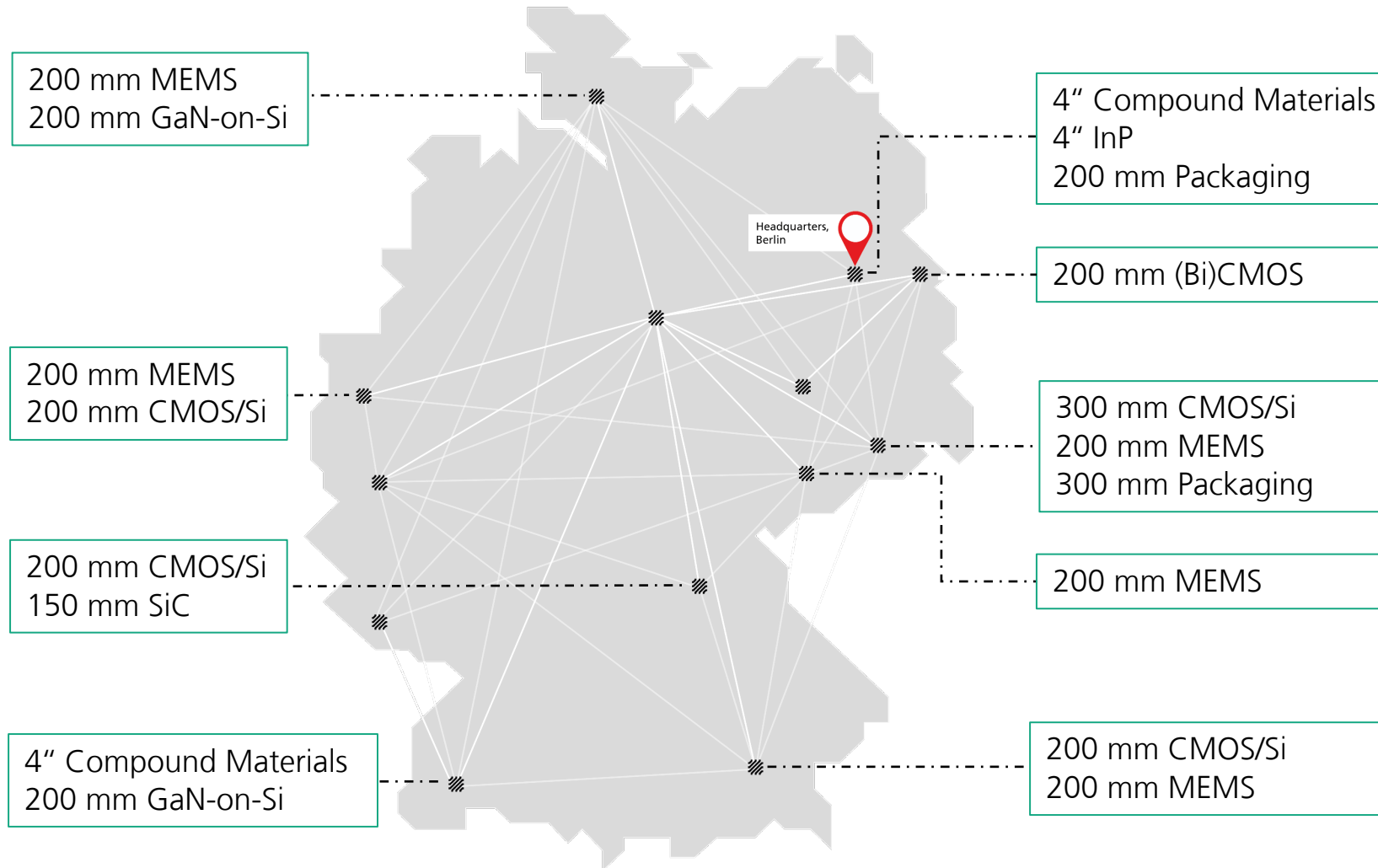
Sensor Systems

Two other technology platforms are currently under construction:
Advanced System Integration and Advanced System Design





FMD Cleanrooms all over Germany



➤ Operation concepts in alignment

- Over 2.200 equipment in 13 cleanrooms all over Germany
- Over 10 Mio moves per year
- Overall size: appr. 11.000 m²
- Wafersizes: 2" till 300 mm



Application Specific Solutions

- 6 specific application topics with collaborative advantage

Technology Platforms

- 6 technology platforms along the value chain

FMD as a strong fundament

- 13 member institutes of the Fraunhofer-Gesellschaft and Leibniz-Gemeinschaft all over Germany

- Transport and Smart Mobility
- Digital Industry
- Health and Wellbeing
- Energy
- Digital Life
- Civil Security and Occupational Safety

- Extended CMOS
- Optoelectronic Systems
- Power Electronics
- MEMS Actuators
- Microwave and Terahertz
- Sensor Systems

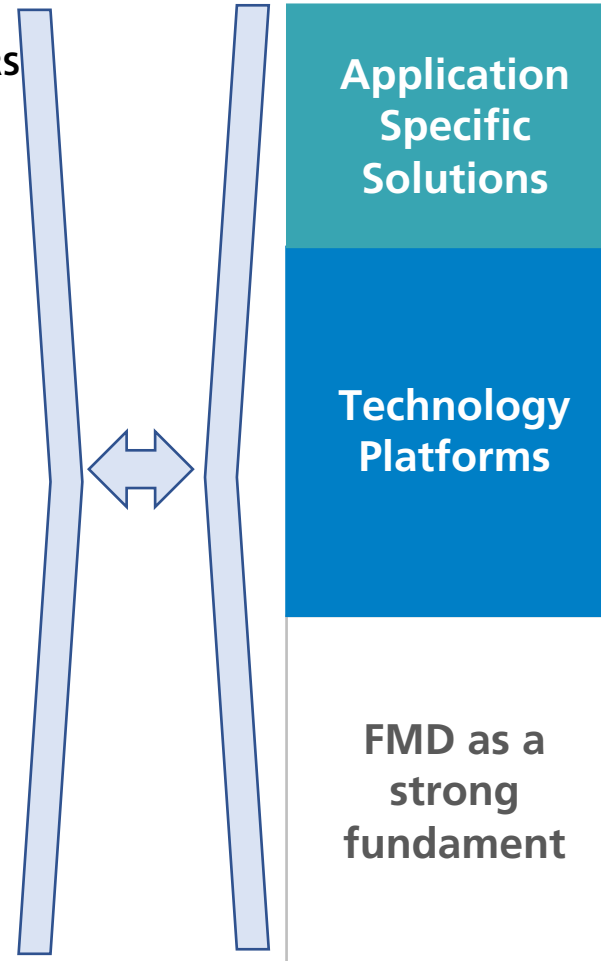


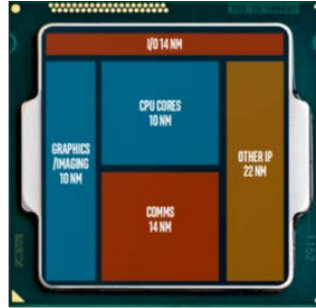
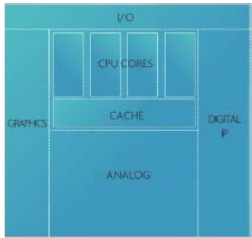
Many synergies between HIR and FMD

IEEE-HIR (Heterogeneous Integration Roadmap)

CHAPTER 2: HIGH PERFORMANCE COMPUTING AND DATA CENTERS
CHAPTER 3: INTERNET OF THINGS (IOT)
CHAPTER 4: MEDICAL, HEALTH & WEARABLES
CHAPTER 5: AUTOMOTIVE
CHAPTER 6: AEROSPACE AND DEFENSE
CHAPTER 7: MOBILE
CHAPTER 8: SINGLE CHIP AND MULTI CHIP INTEGRATION
CHAPTER 9: INTEGRATED PHOTONICS
CHAPTER 10: INTEGRATED POWER ELECTRONICS
CHAPTER 11: MEMS AND SENSOR INTEGRATION
CHAPTER 12: 5G COMMUNICATIONS
CHAPTER 13: CO-DESIGN FOR HETEROGENEOUS INTEGRATION
CHAPTER 14: MODELING AND SIMULATION
CHAPTER 15: MATERIALS AND EMERGING RESEARCH MATERIALS
CHAPTER 16: EMERGING RESEARCH DEVICES
CHAPTER 17: TEST TECHNOLOGY
CHAPTER 18: SUPPLY CHAIN
CHAPTER 19: CYBER SECURITY
CHAPTER 20: THERMAL
CHAPTER 21: SIP AND MODULE SYSTEM INTEGRATION
CHAPTER 22: INTERCONNECTS FOR 2D AND 3D ARCHITECTURES
CHAPTER 23: WAFER-LEVEL PACKAGING (WLP)
CHAPTER 24: RELIABILITY

FMD: Technologies and Applications





SoC System on Chip

Package Integration

Drivers for Heterogeneous Integration in the HPC Segment

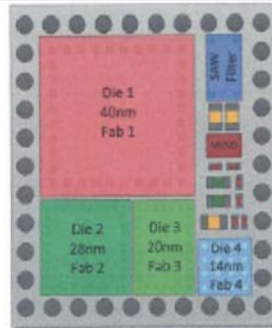
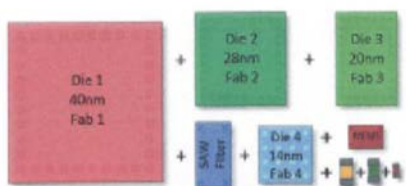
- ⌘ Die cost per unit area increasing with node shrinks
- ⌘ Package IO, latency/BW and power constraining

 **It is all about transferring data!**

Heterogeneous Integration provides a solution that can be in many formats

- ⌘ Design
- ⌘ Wafer-Level Hetero-Integration
- ⌘ Board-Level Hetero-Integration
- ⌘ Specific/different applications

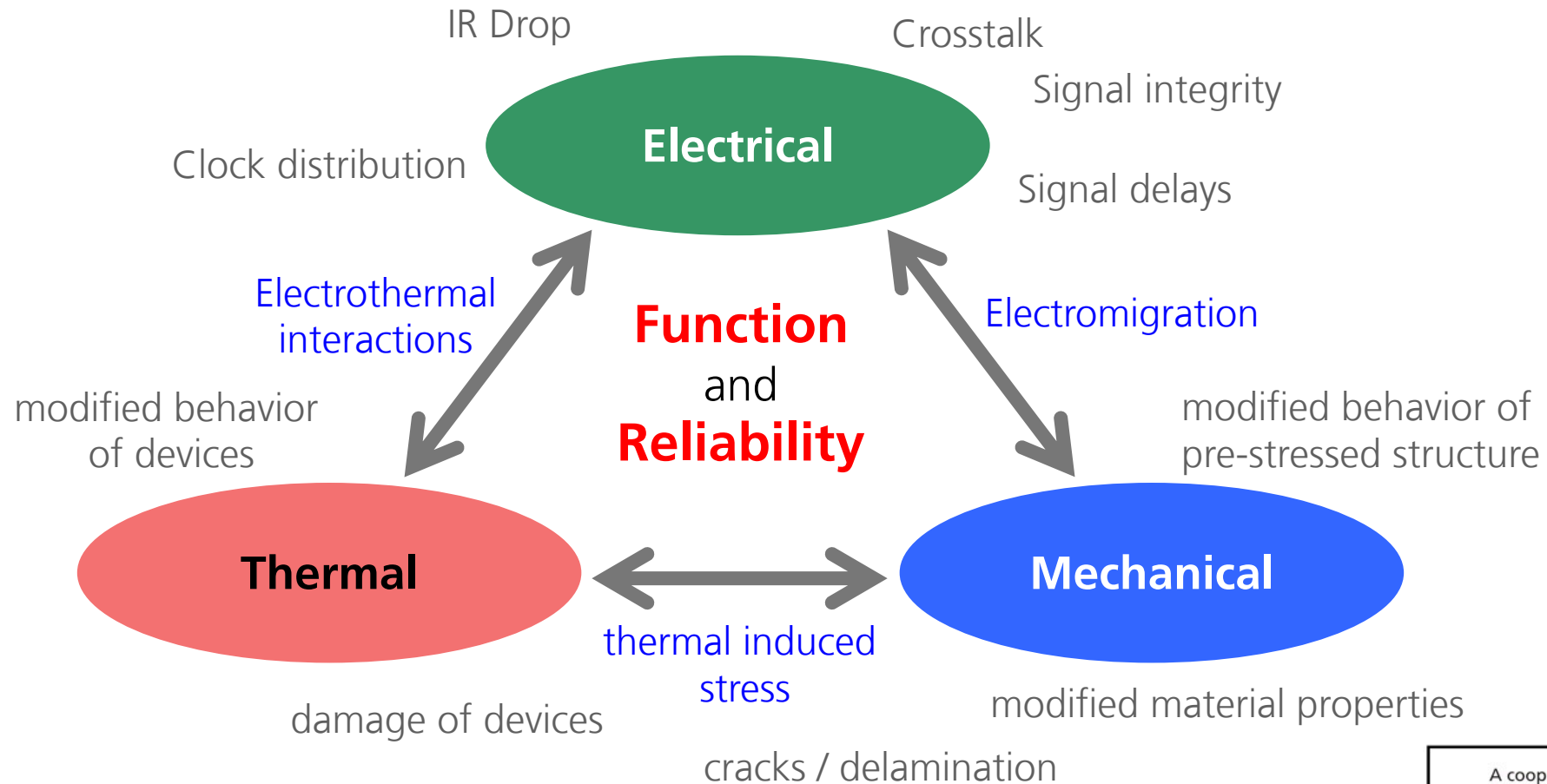
Courtesy J. Hunt, ASE



SiP thru Heterogeneous Integration



Ultra compact miniaturized systems bring new combined physical effects:



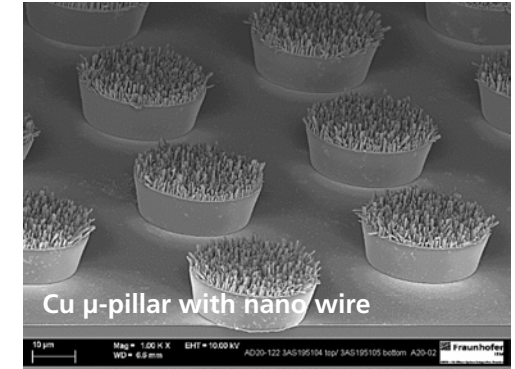
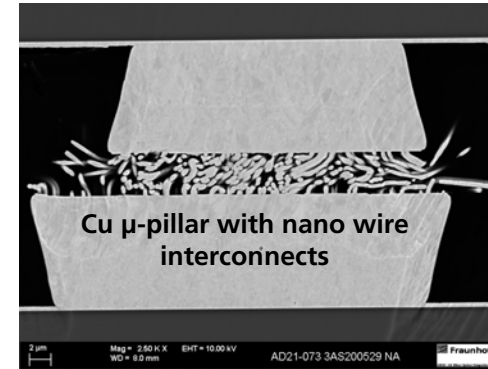


- /// Influences all design steps across all hierarchy levels
- /// **System design**
 - /// Design space exploration over certain chip and package technologies necessary
 - /// Chip-package or chip-package-board-co-optimization necessary
 - /// First tools available to solve parts of the whole problem
- /// **System implementation and system verification**
 - /// Block implementation (analog, digital) can be done by existing flows and tools
 - /// New methods necessary on the boarder between block implementation
 - /// Power delivery networks much more complex
 - /// Interface definition and standardization between different dies



/// Cu-Nano Wire

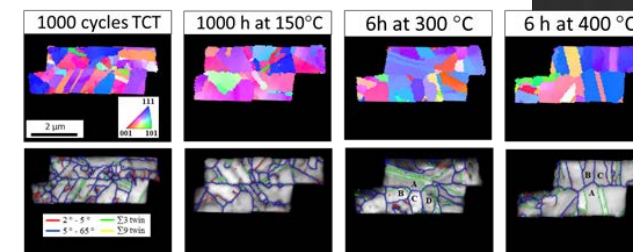
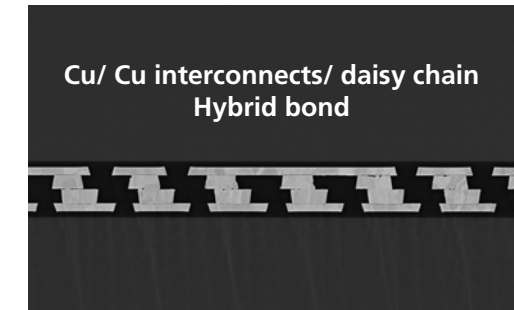
- /// Demonstration on 12" wafer Cu nano wired bumps
- /// High-density interconnects for D2W and W2W Bonding
- /// Room temperature bonding, fluxless process, single metal (Cu)



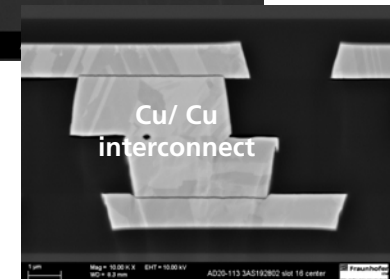
Joint project with NanoWired GmbH

/// Cu/Cu Hybrid Bonding

- /// Hybrid bonding on 300mm wafer size qualified
- /// W2W Bond alignment accuracy (~1μm)
- /// Bond process established
- /// Low Temp. processes < 200°C



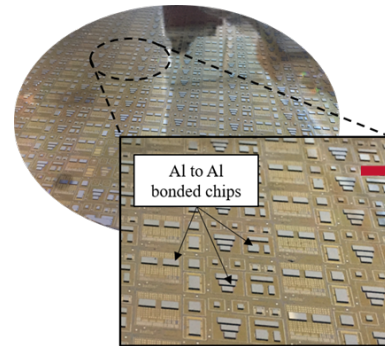
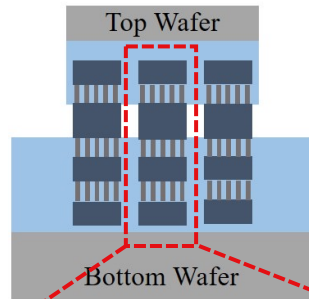
- EBSD method allows detection of Cu grain intergrowth at interface, which can not be detected only by SEM
- Significant intergrowth of Cu grains after storage at 300 and 400 °C (see interface line, growth of grains at triple points)



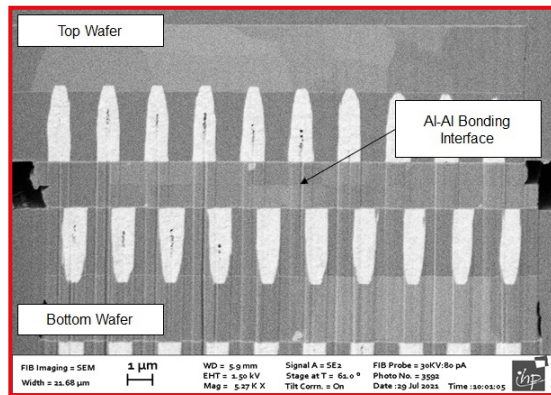
Wafer-Level Hetero-Integration

Wafer-level Heterogeneous Integration for advanced RF applications

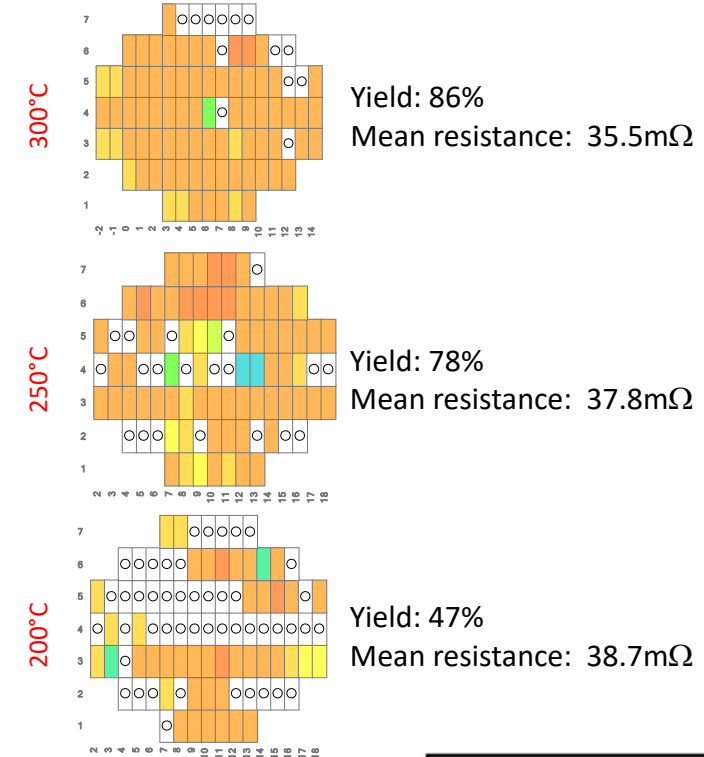
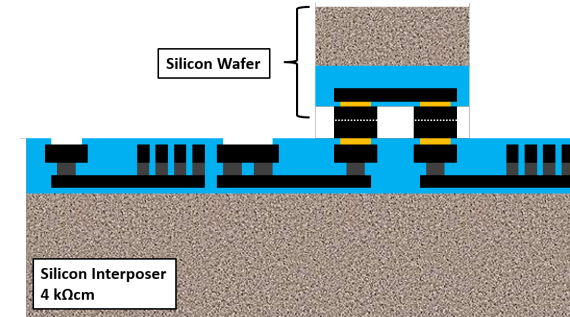
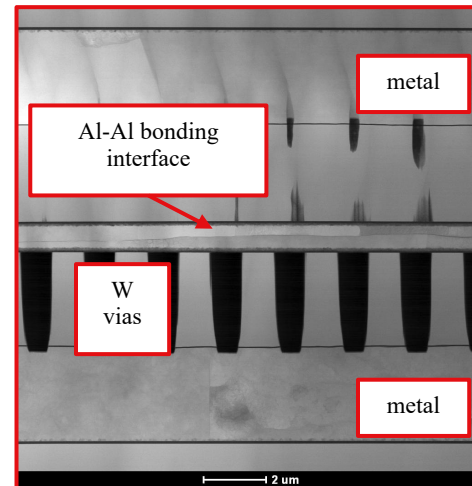
- High-Vacuum Al-Al bonding for 8" wafer platform
- SiGe-BiCMOS co-integration platform (e.g. on Si-RF-interposer)



Final 200mm wafer with Al to Al bonded chips



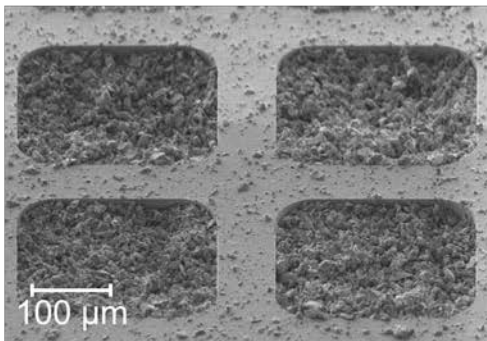
FIB/SEM cross section with 20 µm x 20 µm Al pads bonded at 250 °C for 1 h with 60 kN.



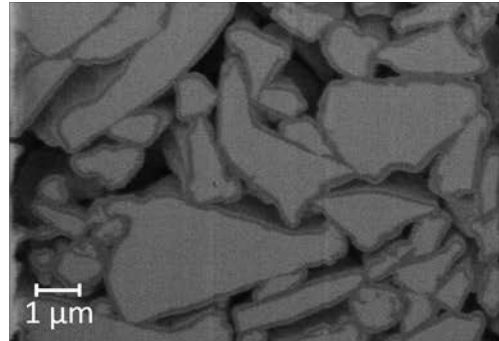
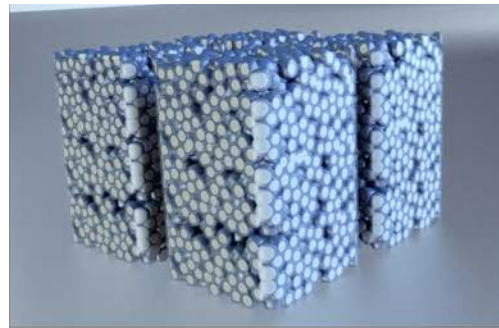


Powder MEMS: substrate-level integration of three-dimensional functional microstructures

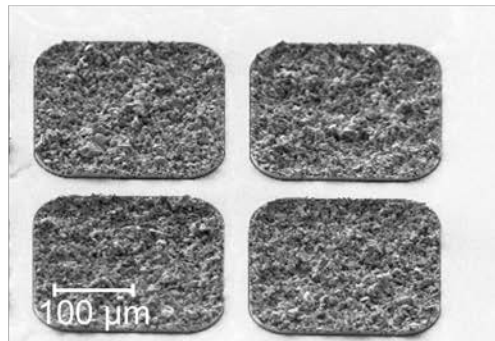
1. Dry-filling of micromolds



2. Solidification with atomic layer deposition



3. Substrate conditioning for post-processing

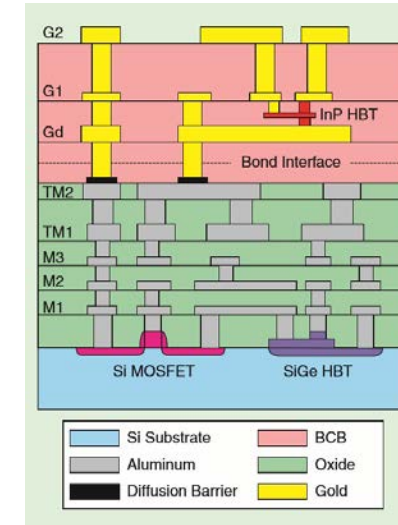


Unique set of characteristics:

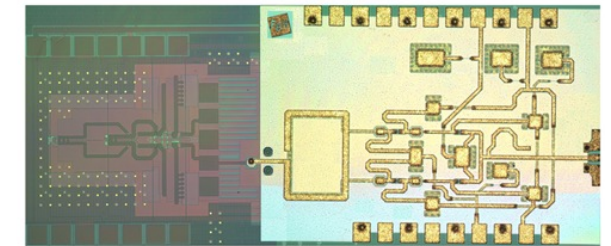
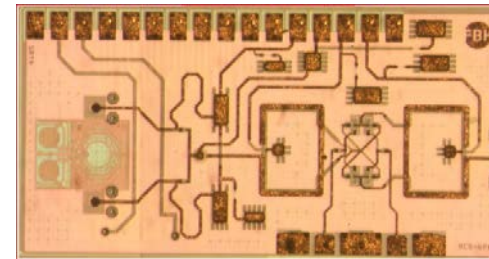
- /// Wide selection of materials
- /// Substrate-level integration
- /// Low process temperature
- /// No organic binder
- /// BEOL compatible
- /// Lateral dim.: 30 – 4000 μm
- /// Thickness: 30 – 1000 μm

Novel wafer-level integrated microcomponents like 3D micromagnets, porous microfluidic structures etc.

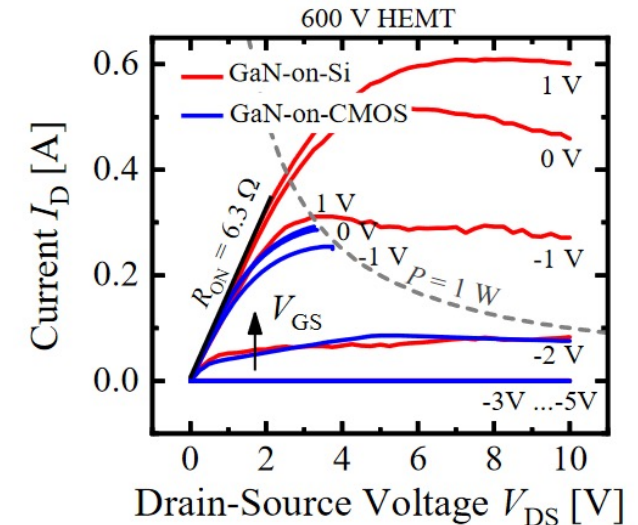
- Combining benefits of III-V technology with BiCMOS
- Integrating InP and BiCMOS circuits on a single chip
 - FBH bipolar InP process
 - IHP BiCMOS process
 - Wafer-bonding and final processing steps in III-V line
- High-frequency performance up to 300 GHz, for 6G and sensors
- Key functions demonstrated
 - Millimeter-wave frequency sources 160 ... 330 GHz
 - W-band up-converter and transmitter



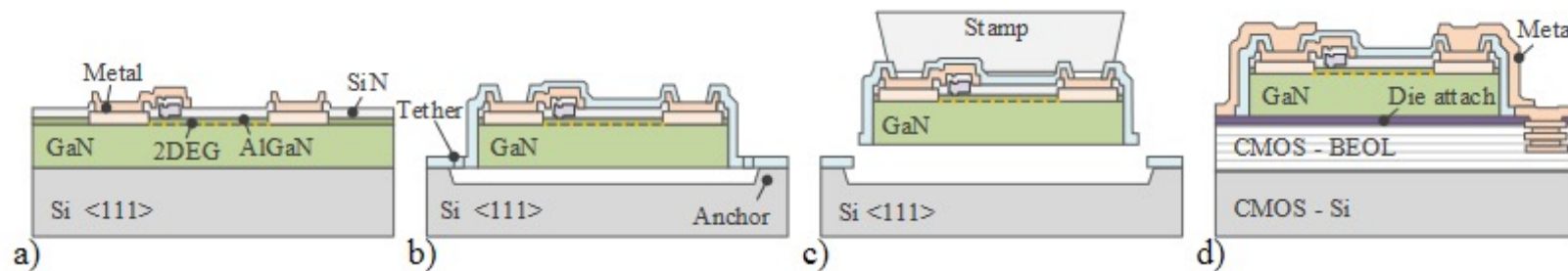
innovations
for high
performance
microelectronics



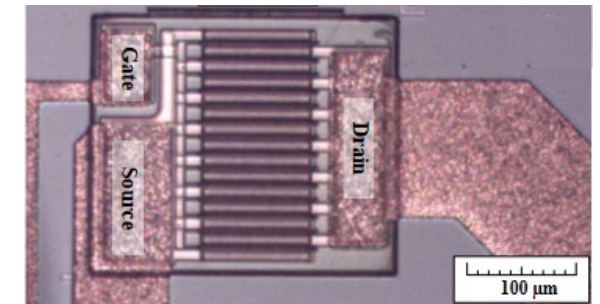
- Monolithic integration of GaN and CMOS devices very challenging due to material and thermal mismatches
- GaN device source wafer, CMOS device target wafer
- Substrate removal of GaN devices and transfer



IV-data on Si and on CMOS



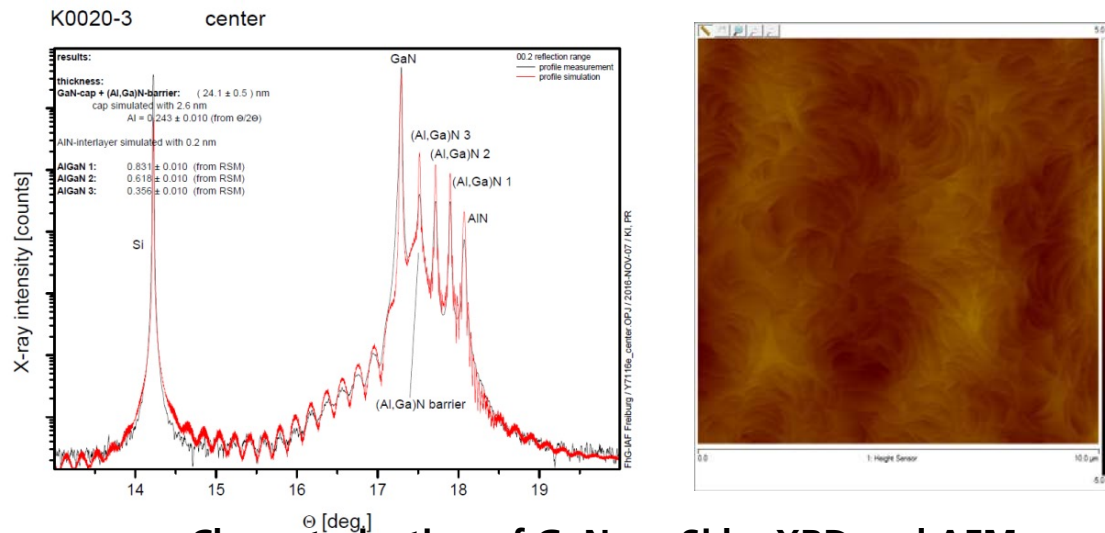
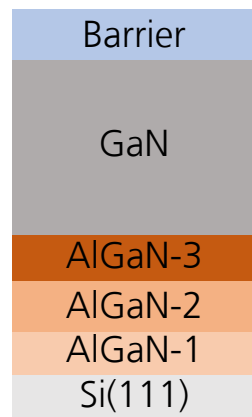
GaN-on-CMOS fabrication steps by transfer printing



Hetero-integrated GaN-HEMT on CMOS

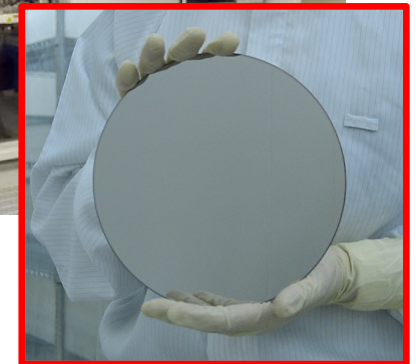
R. Reiner, R. Lerner, P. Waltereit, N. Hansen, S. Moench, A. Fecioru, and D. Gomez, "Characteristics of Hetero-Integrated GaN-HEMTs on CMOS Technology by Micro-Transfer-Printing," 2021 33rd International Symposium on Power Semiconductor Devices and ICs (ISPSD), 2021, pp. 323-326

- GaN-based epitaxial films are grown on large area 200 mm Si substrates by MOCVD
- Tuning of growth parameters to compensate lattice and thermal mismatches
- Alternative to expensive high-resistivity SiC substrates
- Integration of III/V material into CMOS fabrication



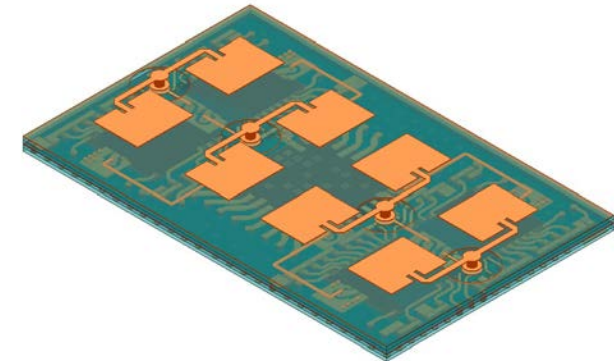
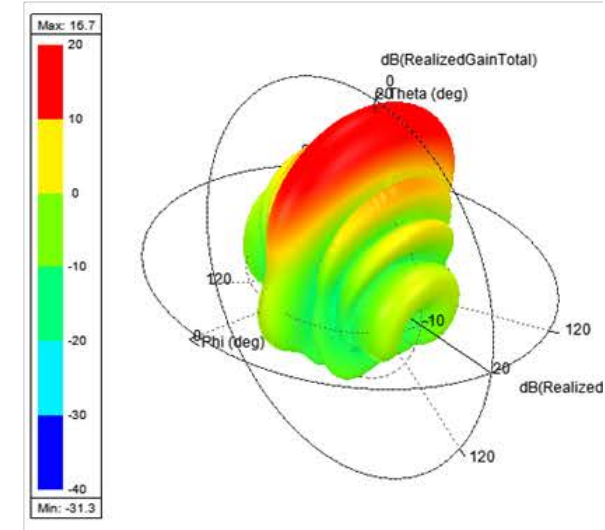
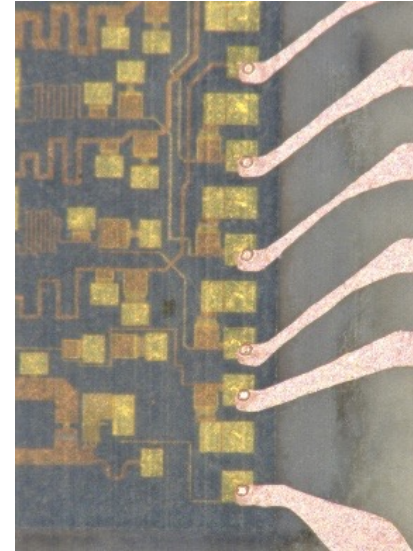
Layer sequence

Characterization of GaN-on-Si by XRD and AFM

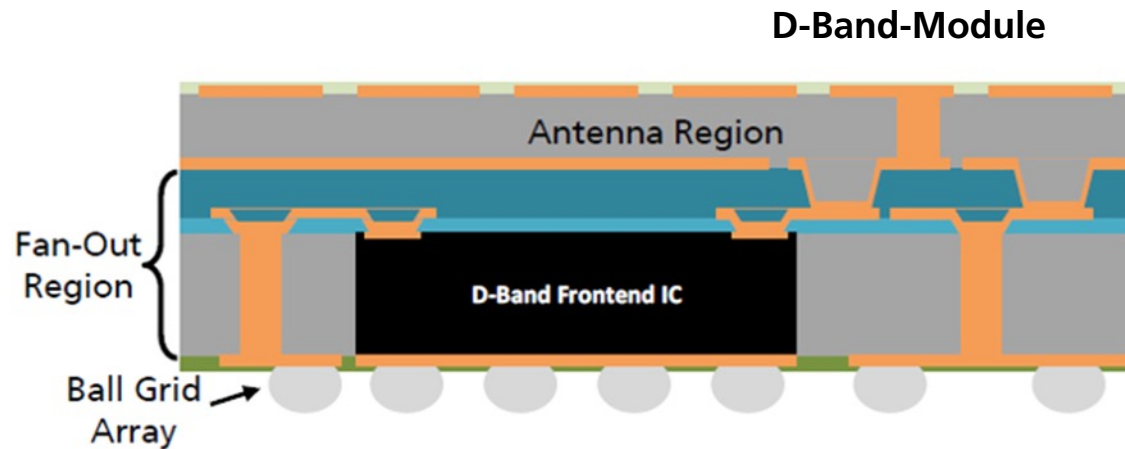


3x200 mm MOCVD reactor for GaN-on-Si devices

- Integration of antennas with RF front-end enables efficient beamforming and multi-user access at millimeter-wave frequency band
- Approach: PCB embedding of GaN and SiGe ICs in antenna-in-package for scalable 5G front-end module
- RF characterization of embedding technology
- Electrical and thermal design of antenna-in-package modules
- Short interconnect between IC and antenna



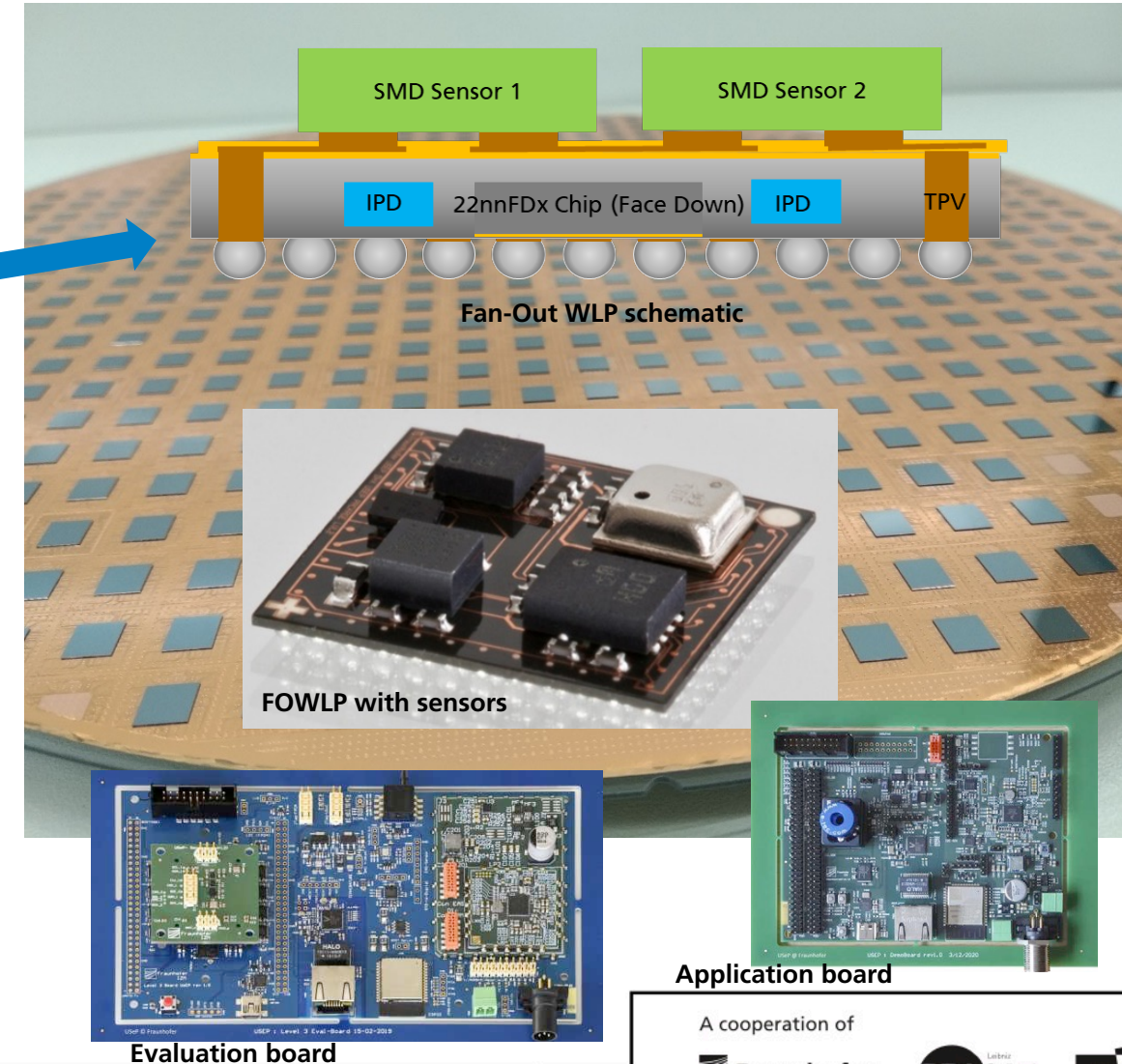
- Development of an ultra-broadband and miniaturized massively MIMO D-band HW module with integrated beamforming capability for 6G
 - Implementation of new baseband architectures taking into account parasitic THz effects in the D-Band module
 - Development of new test procedures and environments for the validation of the modules





Universal Sensor Platform (USEP)

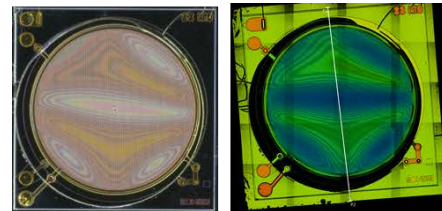
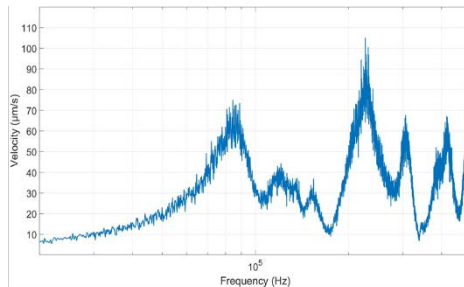
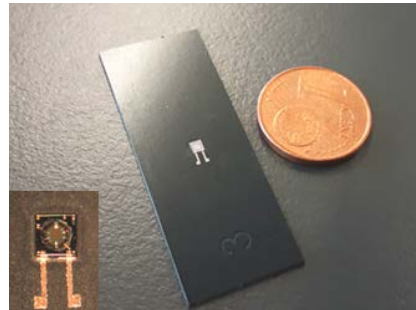
- Development of universal sensor platform (USEP), with which even smaller system providers can shoulder the growing development and production effort for next generation electronics
- Embedded chips
- Package-size: 10mm x 10mm x 0.2mm
- 4 layer thinfilm redistribution
- SMD-assembly of different sensors on top
- Assembly of complete sensor system on evaluation and application boards
- System level validation and functionality demonstration





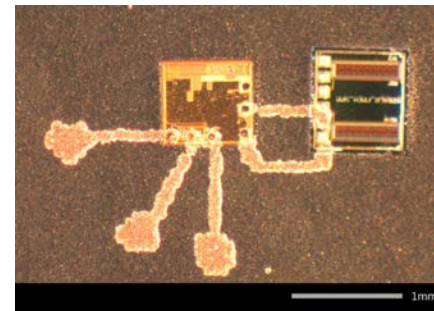
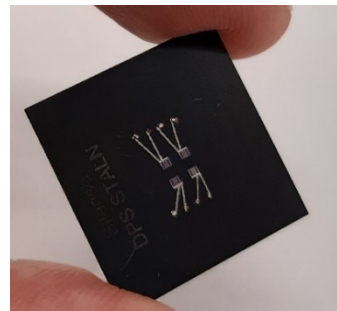
- Integration of MEMS and ASICs for touchless control and gesture sensing with ink-jet printed conductive tracks
- Adapted process flows under ongoing development for
 - MEMS for airborne US with fragile (~300nm thick) membranes

«S»ilense

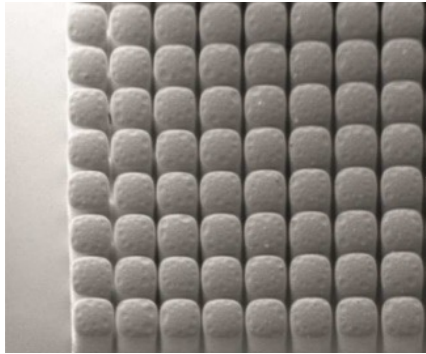


→ Integrity of sensitive membranes demonstrated, stress-decoupling concept under development

- MEMS for underwater US



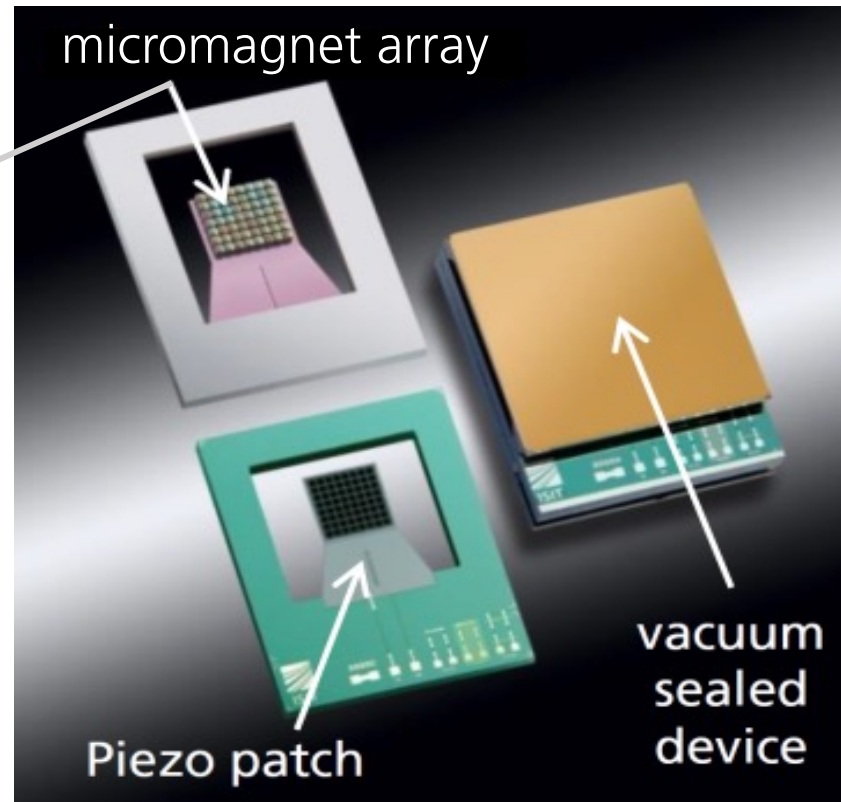
→ Adapted process flow demonstrated, performance testing ongoing



NdFeB micromagnet array
solidified with Al_2O_3 .

Each pixel is $250 \times 250 \mu\text{m}^2$ wide and $500 \mu\text{m}$ high.

$B_r \approx 350 \text{ mT}$, $H_c \approx 1 \text{ T}/\mu_0$



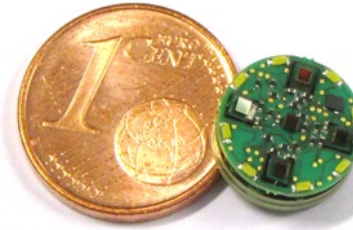
Integrated 3D NdFeB micromagnets allow for

- /// Contactless magnetic excitation
- /// Harvesting of rotary and translational movements
- /// Broadband frequency range (1 Hz – 2 kHz depending on excitation)
- /// Compact design and high-power density due to high tip density

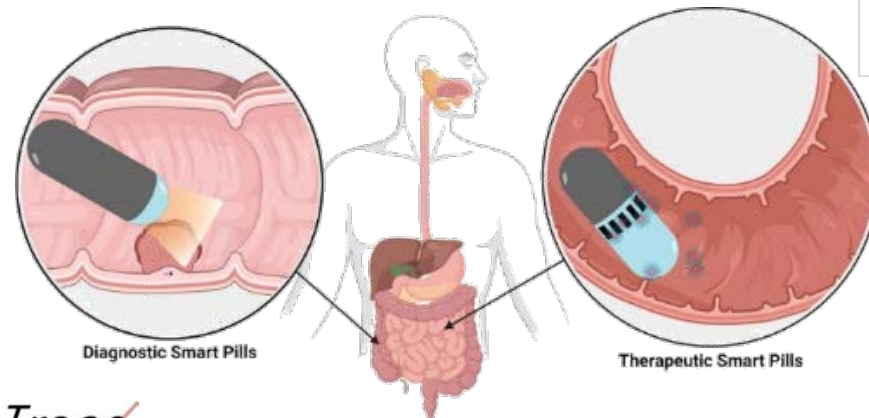
Application: Modular Capsule Endoscopy System

Project EndoTrace

- Use of different miniaturization techniques (e.g. Module stacking, embedding, semi-flex)
- Reduce number of images during the passage through the body (approx. 1/10)
- Onboard image capturing and storage, no external devices needed



Memory / controller module with embedded SMDs



endoTrace

small intestine

Camera module with 5 NanEye M Cameras

Image capturing and memory module

Batteries

Power regulation and position tracking



amun

ovesco
innovation in scope

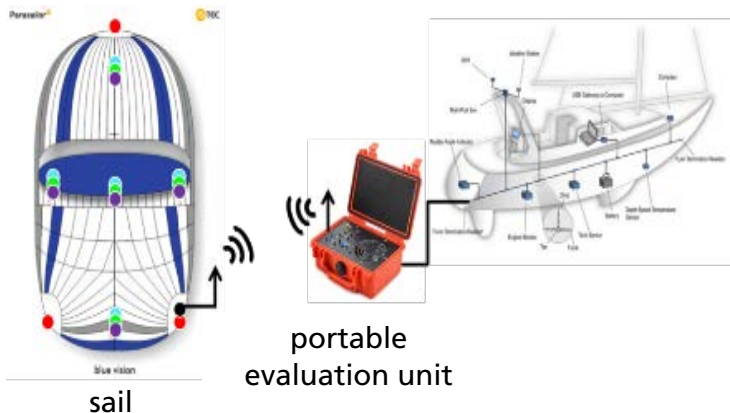
A cooperation of

Fraunhofer
MIKROELEKTRONIK

FBI
Leibniz
Ferdinand
Braun
Institut

ihp

- /// Textile-integrated measuring system (force / pressure / position and orientation in space)
- /// Development of a bus system adapted to large textiles ($\sim 70\text{m}^2$)
- /// Integration of sensor nodes in a high-performance sail
- /// Development of a portable and wireless data evaluation unit

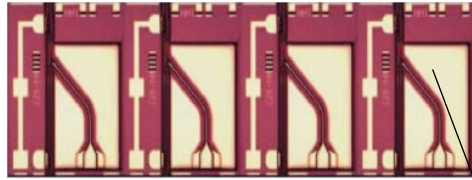


Application: Tb/s Transceiver for Intra Data Center Communication

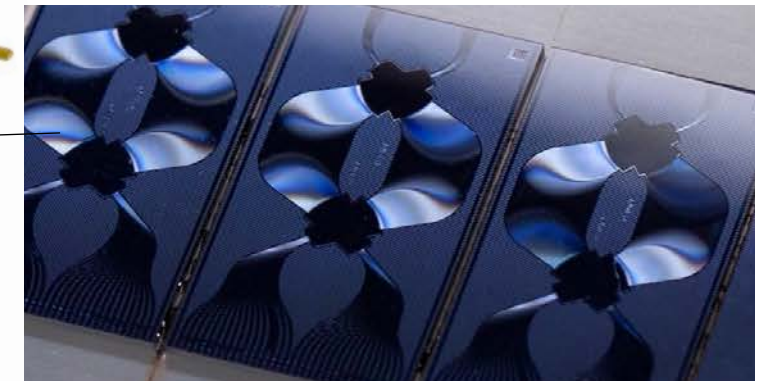
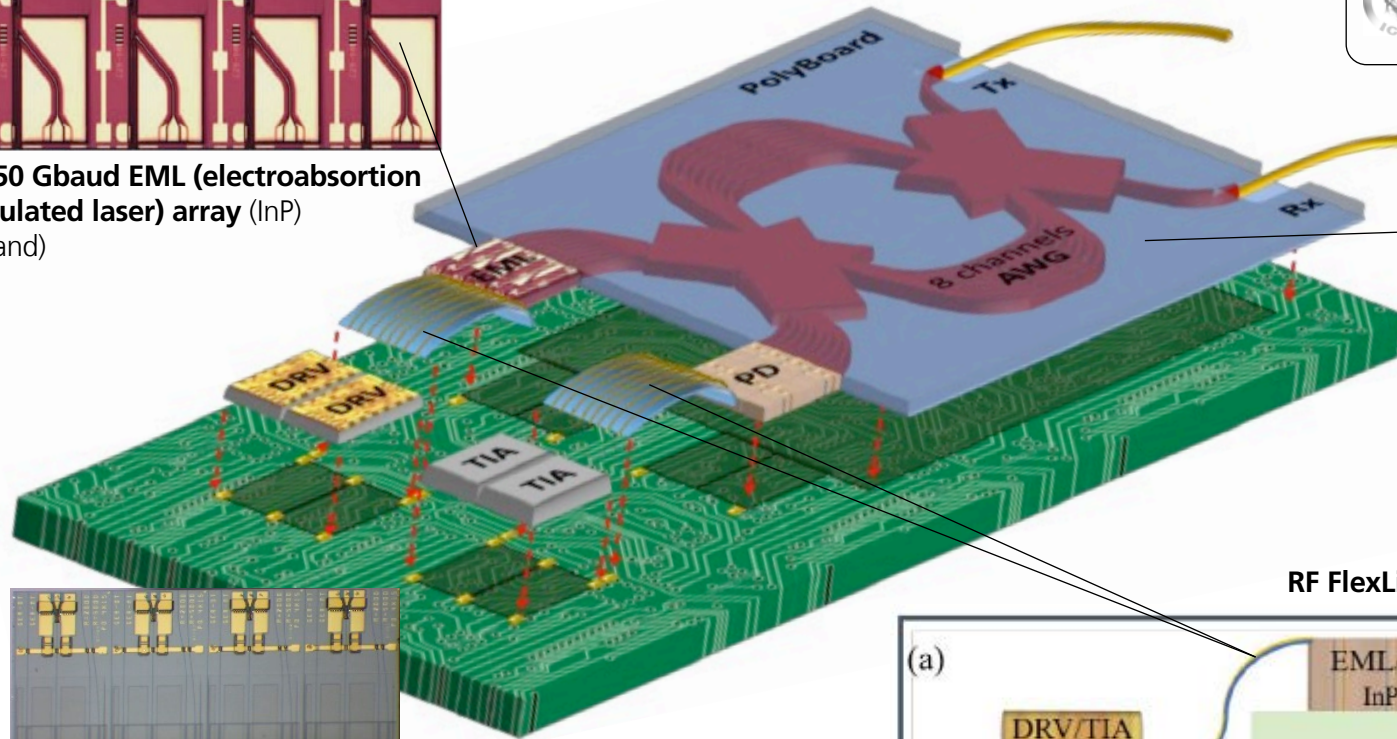
HHI's InP / polymer hybrid integration platform PolyBoard



TERIPHIC

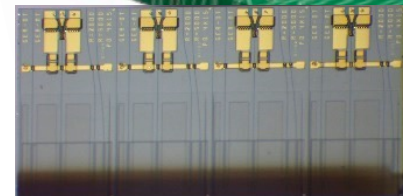
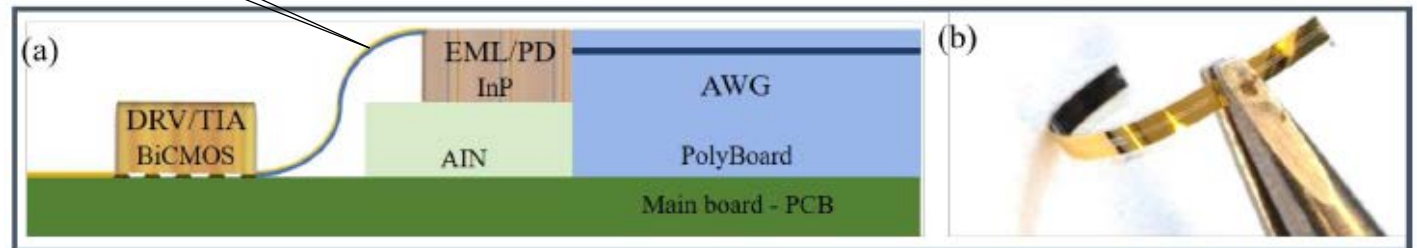


4ch 50 Gbaud EML (electroabsorption modulated laser) array (InP)
(O-band)



16ch AWGs (array wave guide) (PolyBoard, O-band))

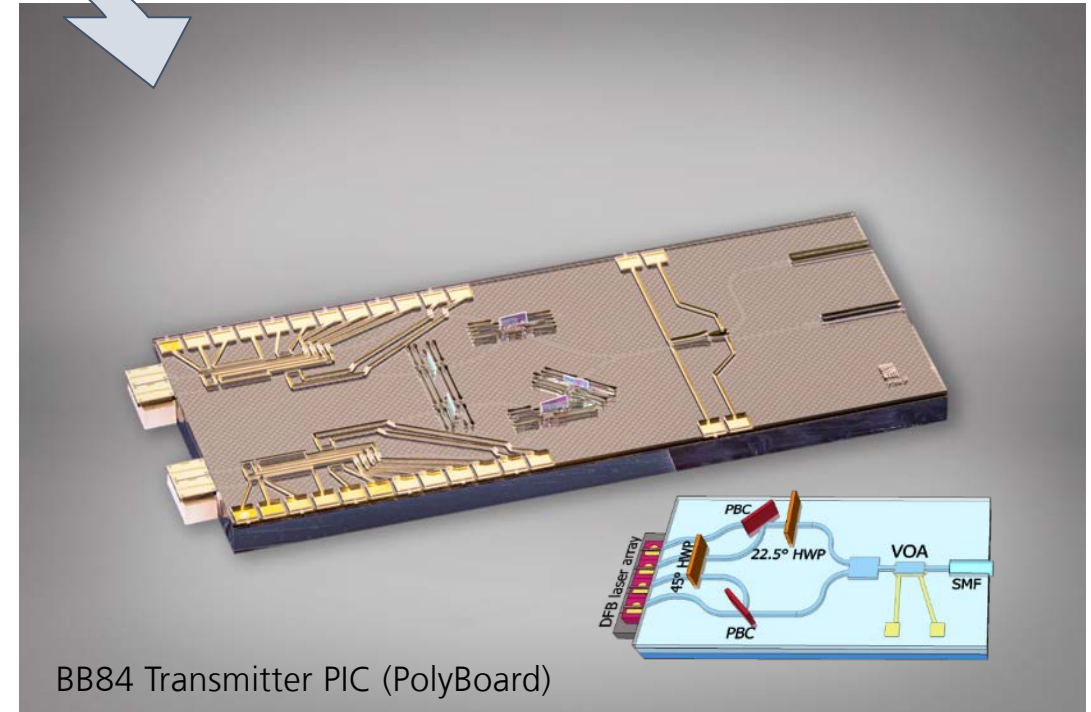
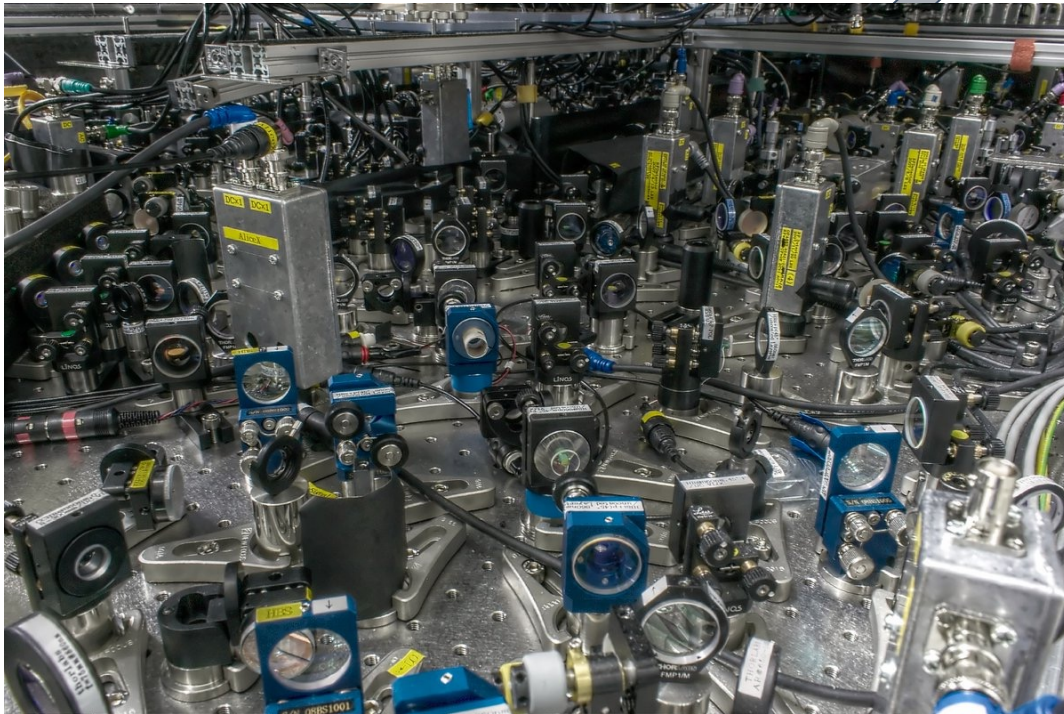
RF FlexLines for interconnecting PICs with DRVs and TIAs (concept and photo)



4ch 50 Gbaud PD (photo diode) array (InP)
(O-band)

Application: Hybrid qPICs for Quantum Communication

Develop a Quantum System-on-Chip platform (QSoC)

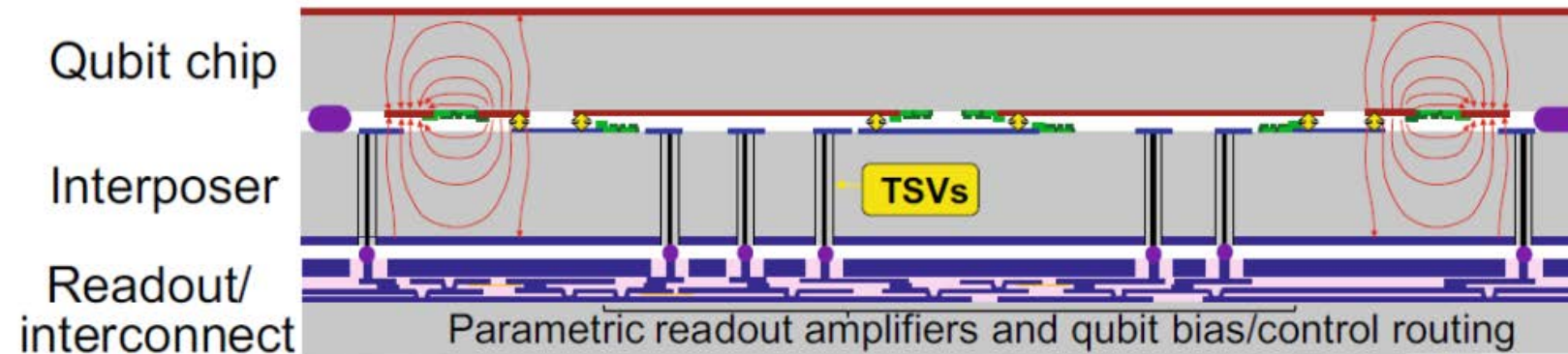


Make Quantum Communication a Commodity





- /// Heterogeneous Integration for future projects (like MQV Bavaria) at Fraunhofer EMFT
- /// 3D Heterogeneous Integration for quantum systems



Source: D. Rosenberg et. al; 3D integrated superconducting qubits; npj Quantum Information (2017)

Challenges:

- /// Introduction of superconducting materials (e.g. In, NbN) for bump and TSV Technology
- /// Connection to metal lines on flex materials with respect to the cryogenic set-up



- /// Building a strong European supply and value chain for new hardware for "Edge AI" applications requires a recognized, strong research alliance
- /// The Alliance for a "Testing and Experimentation Facility for Edge AI" (TEF Edge AI) provides affordable, fast access for small and medium-sized enterprises and system houses
- /// Development of necessary hardware technologies and new components to support energy-efficient "green" AI applications ("Get AI off the cloud")
- /// Open platform for other European partners (excellence and complementarity criteria)
- /// New European Commission funding programs (2021-2028): "Horizon Europe" (including Key Digital Technologies JU) and "Digital Europe" (program to boost digitalization in Europe)



**Forschungsfabrik
Mikroelektronik**
Deutschland



Fraunhofer
MIKROELEKTRONIK



imec





/// Co-Design

- /// Chip design needs a close link to the package design to guarantee high performance and reliability
- /// Multiple domains with different scaling properties have to be considered
- /// Different design libraries are necessary for product development
- /// Thermal, mechanical and electrical analysis are the key for high yield

/// New Materials

- /// Mechanical, electrical and thermal interactions of different materials not yet used as default

/// Cost

- /// Complex systems require new packages
 - ➔ Therefore new package platforms like embedding have to be considered

/// Customer Requirements

- /// Reliability and application specific requirements
- /// High performance is mostly required in HI-applications
- /// Control of temperature requires advanced cooling concepts

/// Test

- /// Application specific tests for complex packages (incl. mixed signal, media, etc.)
- /// Electrical, mechanical and thermal aspects are important



Spokesman of the Fraunhofer Group for Microelectronics
Chairman of the FMD steering committee

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